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#	Paper	IF	Citations
564	On the Contrast of Precipitates Observed with a FE-SEM. <i>Microscopy and Microanalysis</i> , 1999 , 5, 316-31	70.5	
563	A New Parametrization of Mott Scattering Cross Section for Monte Carlo Simulation. <i>Microscopy and Microanalysis</i> , 2000 , 6, 926-927	0.5	
562	Phase Identification Using Electron Backscatter Diffraction in the Scanning Electron Microscope. 2000 , 75-89		13
561	Electric charging of thin films measured using the contrast transfer function. <i>Ultramicroscopy</i> , 2001 , 87, 45-54	3.1	19
560	Electrochemistry of transition metal complex catalysts. 2001 , 46, 3207-3217		6
559	Implant Surface Modification by Biological Multi-layer Systems. 2002, 734, 861		1
558	Accessibility Studies of Sol-Gel Processed Phosphane-Substituted Iridium(I) Complexes in the Interphase. 2002 , 2002, 1998-2006		6
557	Aberration characteristics of immersion lenses for LVSEM. <i>Ultramicroscopy</i> , 2002 , 93, 331-8	3.1	9
556	High-resolution backscatter electron imaging of colloidal gold in LVSEM. 2003 , 211, 212-8		10
555	Special Topics in Scanning Electron Microscopy. 2003 , 195-270		51
554	Specimen Preparation of Hard Materials: Metals, Ceramics, Rocks, Minerals, Microelectronic and Packaged Devices, Particles, and Fibers. 2003 , 537-564		3
553	Classification of single-particle two-dimensional angular optical scattering patterns and heuristic scatterer reconstruction. 2003 , 42, 2689		9
552	Compositional analysis of graded AlxGa($1 \square$)As layers by x-ray energy dispersive spectrometry. 2004 , 22, 1598		
551	Comprehensive failure analysis of leakage faults in bipolar transistors. 2004 , 19, 191-197		3
550	Periodic structure formation by focused electron-beam-induced deposition. 2004 , 22, 2504		33
549	Various magnetic domain structures in a NiMnta martensite exhibiting magnetic shape memory effect. 2004 , 96, 2159-2163		71
548	Results from In-Situ, Real-Time SEM Observations of Grain Growth in Polycrystalline Metal. 2004 , 467-470, 875-880		9

(2005-2004)

547	A Technique for Real-Time, In-Situ SEM Observation of Grain Growth at Elevated Temperatures. 2004 , 467-470, 1385-1388	4
546	Image-processing approach to vibration isolation of a scanning electron microscope. 2004 , 3, 186	1
545	Electron diffraction methods for the analysis of silicon carbide surfaces and the controlled growth of polytype heterostructures. 2004 , 16, S1555-S1578	11
544	Morphology Change of Undoped and Sulfate-Ion-Doped Yttria Powders during Firing. 2004 , 87, 517-519	8
543	Microscopy, mathematics, measurements and Moses. <i>Ultramicroscopy</i> , 2004 , 101, 73-103	1
542	Detecting Defects in Cu Metallization Structures by Electron-Beam Wafer Inspection. 2004 , 151, G440	2
541	Specimen charging on thin films with one conducting layer: discussion of physical principles. Microscopy and Microanalysis, 2004 , 10, 790-6	48
540	Microscopy. 2005,	
539	Low-energy STEM of multilayers and dopant profiles. <i>Microscopy and Microanalysis</i> , 2005 , 11, 97-104 0.5	22
538	Determination of E2 for nitride ceramics using FE-SEM and the Duane-Hunt limit procedure. Microscopy and Microanalysis, 2005, 11, 56-65	7
537	Structural analysis of ion irradiated polycrystalline NiFe/FeMn exchange bias systems. 2005, 45, 213-218	4
536	New technique for in-situ measurement of backscattered and secondary electron yields for the calculation of signal-to-noise ratio in a SEM. 2005 , 217, 235-40	14
535	Probing carrier dynamics in nanostructures by picosecond cathodoluminescence. 2005 , 438, 479-82	131
534	Cross Section Investigations of Compositions and Sub-Structures of Tips Obtained by Focused Electron Beam Induced Deposition. 2005 , 7, 323-331	64
533	On the development and investigation of quaternary Pt-based superalloys with Ni additions. 2005 , 36, 567-575	24
532	Electron Microscope. 2005 ,	
531	Electron Microscope. 2005 ,	
530	Application of Monte Carlo Simulation Method to the Nano-Scale Characterization by Scanning Electron Microscopy. 2005 , 475-479, 4161-4164	1

529	Fabrication of arrays of sub-wavelength nano-apertures in an optically thick gold layer on glass slides for optical studies. 2005 , 16, S273-S277	18
528	Visualization and in situ contacting of carbon nanotubes in a scanning electron microscope. 2005 , 23, 2789	12
527	Chain-oxygen ordering in twin-free YBa2Cu3O7Isingle crystals driven by 20IeV electron irradiation. 2005 , 72,	8
526	Scanning electron microscopy of dopant distribution in semiconductors. 2005 , 86, 101916	11
525	Analysis of magnetization in nanocomposite Nd4.5(Fe,Cr)77B18.5 by electron holography and simulation. <i>Microscopy (Oxford, England)</i> , 2005 , 54, 279-86	3
524	Noise in secondary electron emission: the low yield case. <i>Microscopy (Oxford, England</i>), 2005 , 54, 361-5 1.3	6
523	Sol C el Processed Diamine(diphosphine)ruthenium(II) Complexes for the Catalytic Hydrogenation of #Unsaturated Ketones1,2. 2005 , 17, 3951-3959	7
522	Micrometer-long gold nanowires fabricated using block copolymer templates. 2005 , 21, 7080-2	69
521	Influence of electron recapture by the cathode upon the discharge characteristics in dc planar magnetrons. 2005 , 72, 056402	36
520	Imaging nanometer metallocatalysts formed by photosynthetic deposition of water-soluble transition-metal compounds. 2005 , 109, 5409-13	8
519	Quantitative scanning electron microscope measurement of resistance of incomplete contact holes in ultralarge scale integrated devices. 2005 , 4, 023007	2
518	High-Resolution Scanning Electron Microscopy. 2005 , 325-359	6
517	Intermetallic PtPb Nanoparticles Prepared by Sodium Naphthalide Reduction of Metal-Organic Precursors: Electrocatalytic Oxidation of Formic Acid. 2006 , 18, 5591-5596	102
516	Helium ion microscope: A new tool for nanoscale microscopy and metrology. 2006 , 24, 2871	314
515	Electron-beam-induced topographical, chemical, and structural patterning of amorphous titanium oxide films. 2006 , 110, 23660-8	23
514	Scanning Electron Microscopy in Analysis of Surfaces. 2006 ,	
513	A high-resolution add-on in-lens attachment for scanning electron microscopes. 2001 , 23, 204-10	4
512	Comparison in spatial spreads of secondary electron information between scanning ion and scanning electron microscopy. 2003 , 25, 201-9	9

(2007-2006)

5	511	Using monte carlo simulation for accurate critical dimension metrology of super small isolated poly-lines. 2006 , 25, 291-296	7
5	510	Contrast at very low energies of the gold/carbon specimen for resolution testing. 2006 , 26, 18-24	10
5	509	Monte Carlo simulation of secondary electron and backscattered electron images in scanning electron microscopy for specimen with complex geometric structure. 2005 , 27, 254-67	30
5	508	Generation Mechanism and in situ Growth Behavior of ∃ron Nanocrystals by Electron Beam Induced Deposition. 2006 , 8, 711-714	26
5	507	Understanding the Beneficial Role of Grain Boundaries in Polycrystalline Solar Cells from Single-Grain-Boundary Scanning Probe Microscopy. 2006 , 16, 649-660	144
5	506	Structured surfaces of wide band gap insulators as templates for overgrowth of adsorbates. 2006 , 18, R417-35	26
5	505	The influence of beam energy and oxidation on quantitative carbide analysis in the scanning electron microscope. 2006 , 100, 114902	1
5	504	Bright Contrast Imaging of Carbon Nanofiber-Substrate Interface using Scanning Electron Microscopy. 2006 , 963, 1	
5	503	The solid-state architecture of a metallosupramolecular polyelectrolyte. 2006 , 103, 10202-10206	42
5	502	Dopant regions imaging in scanning electron microscopy. 2006 , 99, 043512	8
5	501	Electron-beam-induced shift in the apparent position of a pinned vortex in a thin superconducting film. 2006 , 73,	1
5	500	Density determination of focused-electron-beam-induced deposits with simple cantilever-based method. 2006 , 88, 031906	32
4	199	Electron beam charging of insulators: A self-consistent flight-drift model. 2006 , 99, 114110	86
4	198	Local electron beam induced reduction and crystallization of amorphous titania films. 2006 , 89, 021902	30
4	197	Cutting of carbon nanotubes assisted with oxygen gas inside a scanning electron microscope. 2006 , 89, 113104	27
4	196	Nanofabrication of Carbon Nanotubes Assisted with Oxygen Gas. 2006,	
4	195	Local Electron Beam Induced Reduction and Crystallization in Electrochemically Deposited Amorphous TiO2 Films. 2006 , 950, 1	
4	194	Acquisition of the Angular Distribution of Backscattered Electrons at Low Energies. 2007, 48, 940-943	15

493	Application of high spatial resolution scanning work function spectroscopy to semiconductor surfaces and interfaces. 2007 , 25, 334	4
492	High throughput defect detection with multiple parallel electron beams. 2007 , 25, 2521	8
491	Depth-Detection Methods for CNT Manipulation and Characterization in a Scanning Electron Microscope. 2007 ,	5
490	Secondary electron imaging at gas pressures in excess of 1kPa. 2007 , 91, 053122	15
489	Electron flux controlled switching between electron beam induced etching and deposition. 2007 , 101, 054309	43
488	Analytic models for the kinetics of generating a voltage contrast signal from contact plugs used in integrated circuits. 2007 , 101, 064913	4
487	A Novel Laser Powered Heating Stage for In Situ Investigations in a SEM. 2007 , 558-559, 909-914	3
486	Contrast and resolution versus specimen thickness in low energy scanning transmission electron microscopy. 2007 , 101, 114917	24
485	Atomic force microscopy (AFM), transmission electron microscopy (TEM) and scanning electron microscopy (SEM) of nanoscale plate-shaped second phase particles. 2007 , 87, 2427-2460	6
484	Local Tuning of Conductivity in Amorphous Titanium Oxide Films by Selective Electron Beam Irradiation. 2007 , 111, 13972-13980	10
483	Introduction to the focused ion beam system. 1-30	3
482	Imaging using electrons and ion beams. 87-125	2
481	High-density FIB-SEM 3D nanotomography: with applications of real-time imaging during FIB milling. 146-186	3
480	Secondary electron imaging of SiC-based structures in secondary electron microscope. 2007 , 601, 4428-4432	14
479	Charge Contrast Imaging of Nonconductive Samples in the High-Vacuum Field Emission Scanning Electron Microscope. 2007 , 29, 230-237	2
478	Tensile tests of polymers at low temperatures in the environmental scanning electron microscope: an improved cooling platform. 2007 , 29, 261-9	12
477	The trajectories of secondary electrons in the scanning electron microscope. 2006 , 28, 245-56	12
476	Depth-detection methods for microgripper based CNT manipulation in a scanning electron microscope. 2008 , 4, 27-36	39

(2008-2008)

475	Simulated SEM images for resolution measurement. 2008 , 30, 381-91	33
474	Secondary electron emission from freely supported nanowires. 2008, 104, 114306	19
473	Spherical EBSD. 2008 , 230, 472-86	41
472	Canny optimization technique for electron microscope image colourization. 2008 , 232, 313-34	5
471	Scanning Electron Microscopy (SEM). 2008 , 87-120	1
470	Quantitative voltage contrast method for electron irradiated insulators in SEM. 2008, 41, 175304	4
469	A critical literature review of focused electron beam induced deposition. 2008, 104, 081301	401
468	Introduction to Polymer Morphology. 2008 , 1-25	1
467	Gas-assisted focused electron beam and ion beam processing and fabrication. 2008, 26, 1197	792
466	Real-time Object Tracking Inside an SEM. 2008 , 103-128	1
465	A review of analytical methods for the identification and characterization of nano delivery systems in food. 2008 , 56, 8231-47	186
464	Laser powered heating stage in a scanning electron microscope for microstructural investigations at elevated temperatures. 2008 , 79, 043902	20
463	Image Formation in the Microscope. 2008 , 67-129	
462	Probe current, probe size, and the practical brightness for probe forming systems. 2008 , 26, 949	53
461	High resolution radially symmetric nanostructures from simultaneous electron beam induced etching and deposition. 2008 , 19, 025303	29
460	Fabrication and characterization of cellular iron nanocrystalline film. 2008 , 19, 135302	5
459	Bent graphite surfaces as guides for cluster diffusion and anisotropic growth. 2008, 77,	13
458	Superior imaging resolution in scanning helium-ion microscopy: A look at beam-sample interactions. 2008 , 104, 063504	52

457	Controlled focused electron beam-induced etching for the fabrication of sub-beam-size nanoholes. 2008 , 92, 043124	17
456	Automated Nano-Assembly in the SEM I: Challenges in setting up a warehouse. 2008, 41, 12751-12756	1
455	On the Energy Distribution of Secondary Electrons Emitted from Metals. 2008, 15, 186-194	10
454	Parasitic effects on nanoassembly processes. 2009 ,	2
453	Vision feedback for automated nanohandling. 2009 ,	1
452	Application and further development of advanced image processing algorithms for automated analysis of serial section image data. 2009 , 17, 025002	42
451	Positioning Pd catalyst particles for carbon nanotube growth using charge patterns created with a scanning electron microscope. 2009 , 27, 3048	
450	Design of a multiple-electron-beam imaging technique for surface inspection. 2009 , 27, 3256	
449	Dose and energy dependence of mechanical properties of focused electron-beam-induced pillar deposits from Cu(C5HF6O2)2. 2009 , 20, 385304	26
448	Noise characteristics of the gas ionization cascade used in low vacuum scanning electron microscopy. 2009 , 106, 014904	5
447	VISUAL FEEDBACK METHODS FOR NANOHANDLING AUTOMATION. 2009 , 06, 159-169	5
446	Unusual secondary electron emission behavior in carbon nanotube forests. 2009 , 31, 221-8	14
445	Gaussian-Taylor signal-to-noise ratio estimation for scanning electron microscope images. 2009 , 236, 18-34	
444	Tin-containing fluoride solutions as anti-erosive agents in enamel: an in vitro tin-uptake, tissue-loss, and scanning electron micrograph study. 2009 , 117, 427-34	101
443	Generation of clean iron structures by electron-beam-induced deposition and selective catalytic decomposition of iron pentacarbonyl on Rh(110). 2009 , 25, 11930-9	35
442	Effect of catalyst shape and etchant composition on etching direction in metal-assisted chemical etching of silicon to fabricate 3D nanostructures. 2009 , 3, 4033-42	119
441	Materials Science and Engineering. 2009 , 73-222	2
440	Spherical Kikuchi Maps and Other Rarities. 2009 , 65-80	4

439	Fusion of AFM and SEM scans. 2009 ,	5
438	Contact MicromanipulationBurvey of Strategies. 2009 , 14, 504-514	77
437	Quantification of sample thickness and in-concentration of InGaAs quantum wells by transmission measurements in a scanning electron microscope. <i>Microscopy and Microanalysis</i> , 2010 , 16, 604-13	15
436	Grain Contrast Imaging in UHV SLEEM. 2010 , 51, 292-296	13
435	Mapping the Local Density of States by Very-Low-Energy Scanning Electron Microscope. 2010 , 51, 214-218	5
434	Elektronen als Insichtbare TinteIHerstellung von Nanostrukturen durch lokale elektronenstrahlinduzierte Aktivierung von SiOx. 2010 , 122, 4774-4778	7
433	Electrons as "invisible ink": fabrication of nanostructures by local electron beam induced activation of SiOx. 2010 , 49, 4669-73	66
432	Characterization of the interphase in an aluminium/epoxy joint by using controlled pressure scanning electron microscopy coupled with an energy dispersive X-ray spectrometer. 2010 , 41, 105-111	6
431	A Monte Carlo simulation study on the image resolution in scanning electron microscopy. 2010 , 42, 1096-109	9 ₇
430	Mechanism of action of tin-containing fluoride solutions as anti-erosive agents in dentine - an in vitro tin-uptake, tissue loss, and scanning electron microscopy study. 2010 , 118, 376-84	62
429	Depth measurements of etch-pits in GaN with shape reconstruction from SEM images. 2010 , 237, 242-5	5
428	Lagrange time delay estimation for scanning electron microscope image magnification. 2010 , 237, 111-8	
427	Principles of depth-resolved Kikuchi pattern simulation for electron backscatter diffraction. 2010 , 239, 32-45	50
426	Scanning ultrafast electron microscopy. 2010 , 107, 14993-8	92
425	Wettability study using transmitted electrons in environmental scanning electron microscope. 2010 , 96, 183109	23
424	Tungsten as a CMOS compatible catalyst for the Metal-assisted Chemical Etching of silicon to create 2D and 3D nanostructures. 2010 ,	2
423	Visualizing nanoscale electronic band alignment at the La2/3Ca1/3MnO3/Nb:SrTiO3 interface. 2010 , 82,	22
422	Secondary electron yield of multiwalled carbon nanotubes. 2010 , 97, 261902	17

421	High-resolution x-ray observation of unstained samples by a newly developed SGXM. 2010 , 21, 295501	2
420	Simulation of scanning electron microscope images taking into account local and global electromagnetic fields. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2010 , 28, C6C41-C6C47	8
419	Simulating STEM imaging of nanoparticles in micrometers-thick substrates. <i>Microscopy and Microanalysis</i> , 2010 , 16, 795-804	35
418	Electron microscopy to study membrane electrode assembly (MEA) materials and structure degradation. 2010 ,	O
417	Nanoscale fabrication by intrinsic suppression of proximity-electron exposures and general considerations for easy and effective topdown fabrication. 2010 , 20, 125015	6
416	Effect of sample bias on backscattered ion spectroscopy in the helium ion microscope. 2010 , 28, 1377-1380	6
415	Fast focus-based depth detection for manipulation in scanning electron microscopes. 2011,	
414	Use of Neural Network and Genetic Algorithm to Model Scanning Electron Microscopy for Enhanced Image of Material Surfaces. 2011 , 26, 382-387	5
413	4D scanning ultrafast electron microscopy: visualization of materials surface dynamics. 2011 , 133, 7708-11	71
412	Rutherford backscattering oscillation in scanning helium-ion microscopy. 2011 , 109, 064311	7
411	Reference material for transmission electron microscope calibration. 2011 , 22, 094014	9
410	Energy-Dispersive X-Ray Spectroscopy (EDXS). 2011 , 293-310	1
409	Monte Carlo simulation of electron scattering and secondary electron emission in individual multiwalled carbon nanotubes: A discrete-energy-loss approach. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011 , 29, 041803	7
408	Selective Backscattered Electron Imaging of Material and Channeling Contrast in Microstructures of Scale on Low Carbon Steel Controlled by Accelerating Voltage and Take-off Angle. 2011 , 51, 1487-1491	24
407	Image contrast in the backscattered electron mode in scanning electron microscopy and microtomography. 2011 , 75, 1234-1239	3
406	Single image signal-to-noise ratio estimation for magnetic resonance images. 2011 , 35, 39-48	8
405	A hypothetical model for predicting the toxicity of high aspect ratio nanoparticles (HARN). 2011 , 13, 6683-6698	10
404	Femtosecond laser interaction with pulsed-laser deposited carbon thin films of nanoscale thickness. 2011 , 102, 27-33	6

403	Three-dimensional electron microscopy simulation with the CASINO Monte Carlo software. 2011 , 33, 135-46		207
402	Resizing metal-coated nanopores using a scanning electron microscope. 2011 , 7, 2736-41		6
401	Wavelength-dispersive spectral analysis and quantification of monazites by electron-probe microanalysis. 2011 , 66, 67-73		2
400	Miniaturization of grayscale images. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011 , 29, 06F313	.3	4
399	A new scanning electron microscopy approach to image aerogels at the nanoscale. 2011 , 22, 175704		3
398	In situ scanning electron microscopy. 2011 , 16, 68-78		17
397	Anti-phase domains in cubic GaN. 2011 , 110, 123512		24
396	Optimizing a low-energy electron diffraction spin-polarization analyzer for imaging of magnetic surface structures. 2011 , 82, 033704		31
395	Analysis of charging effects on highly resistive materials under electron irradiation by using transient-absorbed-current method. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011 , 29, 031209	.3	6
394	Total electron emission yield measurement of insulator by a scanning small detector. 2011 , 99, 152101		16
393	Scanning Electron Microscopy and Energy-Dispersive X-Ray Spectrometry. 2011 , 85-130		1
392	Sum frequency generation-compressive sensing microscope. 2011 , 135, 194202		20
391	Registration of AFM and SEM Scans Using Local Features. 2011 , 5, 249-270		1
390	Strain Mapping by Scanning Low Energy Electron Microscopy. 2011 , 465, 338-341		4
389	Three-dimensional electron energy deposition modeling of cathodoluminescence emission near threading dislocations in GaN and electron-beam lithography exposure parameters for a PMMA resist. <i>Microscopy and Microanalysis</i> , 2012 , 18, 1220-8	0.5	17
388	Photoresist Shrinkage Caused by Single-Line Scan of Electron Beam. 2012 , 51, 06FB10		2
387	Simulation of electron scattering in a scanning electron microscope for subsurface metrology. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2012, 30, 06F701	.3	3
386	On density estimation with superkernels. 2012 , 24, 613-627		1

385	Scanning Helium Ion Microscopy. 2012 , 1		2
384	Correlative light and electron microscopy using cathodoluminescence from nanoparticles with distinguishable colours. 2012 , 2, 865		61
383	Spatial resolution optimization of backscattered electron images using Monte Carlo simulation. <i>Microscopy and Microanalysis</i> , 2012 , 18, 628-37	0.5	7
382	Charged Particle Microscopy: Why Mass Matters. 2012 , 20, 16-22		21
381	Effects of ion barrier film on image noise in generation III image tube. 2012 ,		
380	Influence of Etchants on Quantitative/Qualitative Evaluations of the 🛭 Precipitates in a Nickel-Base Superalloy. 2012 , 1, 290-296		12
379	Characterization of the local crystallinity via reflectance of very slow electrons. 2012, 100, 261602		4
378	. 2012 , 40, 291-297		27
377	Measurement Techniques of Aligned Carbon Nanotubes. <i>Nanoscience and Technology</i> , 2012 , 157-182	0.6	
376	Detection of circulating cancer cells using electrocatalytic gold nanoparticles. 2012 , 8, 3605-12		53
375	Hierarchical super-structure identified by polarized light microscopy, electron microscopy and nanoindentation: Implications for the limits of biological control over the growth mode of abalone sea shells. 2012 , 5, 19		14
374	A facile method to observe graphene growth on copper foil. 2012 , 23, 475705		30
373	Fundamental proximity effects in focused electron beam induced deposition. 2012, 6, 286-94		49
372	Grain structure visualization with surface skimming ultrasonic waves detected by laser vibrometry. 2012 , 101, 074101		8
371	Introduction to Scanning Electron Microscopy. 2012 , 1-37		0
370	Secondary electron image formation of a freestanding &i3N4 nanobelt. 2012 , 111, 054316		
369	Monte Carlo simulation of secondary electron images for real sample structures in scanning electron microscopy. 2012 , 34, 145-50		34
368	Characterization and Low-Temperature Resistivity of Thin CeIn3 Films Prepared by Co-sputtering. 2012 , 168, 90-97		1

Observation of epitaxially ordered twinned zinc aluminate Banoblades on c-sapphire. **2012**, 23, 758-765

366	Experimental Techniques. 2013 , 1-30	1
365	Characterization of dual-phase steel microstructure by combined submicrometer EBSD and EPMA carbon measurements. <i>Microscopy and Microanalysis</i> , 2013 , 19, 996-1006	61
364	Test object for calibrating the transmission electron microscope. 2013 , 42, 155-159	
363	Simulation of the range of keV-energy electrons in a dielectric target upon spatial charge accumulation. <i>Journal of Surface Investigation</i> , 2013 , 7, 268-270	1
362	Scanning Electron Microscopy. 2013 , 127-161	
361	Deflection properties of an electrostatic electron lens with a shifted electrode. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2013 , 31, 06F702	2
360	Fabrication of p-type silicon nanowires for 3D FETs using focused ion beam. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2013 , 31, 06FA01	5
359	Simulation of the current induced by 63Ni beta radiation. <i>Journal of Surface Investigation</i> , 2013 , 7, 852-8555	12
358	Environmental scanning ultrafast electron microscopy: structural dynamics of solvation at interfaces. 2013 , 52, 2897-901	23
357	Study of void observation technique using scanning electron microscopy. 2013 , 107, 91-96	
356	A stitching algorithm for measuring large areas using scanning electron microscopes. 2013 , 14, 147-151	3
355	Helium Ion Microscopy. 2013 , 461-497	9
354	Laboratory-based cryogenic soft x-ray tomography with correlative cryo-light and electron microscopy. <i>Microscopy and Microanalysis</i> , 2013 , 19, 22-9	21
353	Nanometres-resolution Kikuchi patterns from materials science specimens with transmission electron forward scatter diffraction in the scanning electron microscope. 2013 , 250, 1-14	68
352	Is it possible to measure diameters of metal nanoparticles using BSE imaging in FESEM?. 2013 , 44, 159-66	2
351	Modification on Single-Layer Graphene Induced by Low-Energy Electron-Beam Irradiation. 2013 , 117, 10079-10085	34
350	Monte Carlo simulation of CD-SEM images for linewidth and critical dimension metrology. 2013 , 35, 127-39	27

349	Simulation of FIB-SEM images for analysis of porous microstructures. 2013 , 35, 189-95		25
348	Comparison of channeling contrast between ion and electron images. <i>Microscopy and Microanalysis</i> , 2013 , 19, 344-9	0.5	22
347	TRIP steel microstructure visualized by slow and very slow electrons. <i>Microscopy (Oxford, England)</i> , 2013 , 62, 589-96	1.3	9
346	Non-destructive and rapid evaluation of chemical vapor deposition graphene by dark field optical microscopy. 2013 , 103, 043119		24
345	Acquisition parameters optimization of a transmission electron forward scatter diffraction system in a cold-field emission scanning electron microscope for nanomaterials characterization. 2013 , 35, 375-8	36	26
344	Three-dimensional imaging of copper pillars using x-ray tomography within a scanning electron microscope: a simulation study based on synchrotron data. 2013 , 84, 023708		4
343	High-resolution photocurrent microscopy using near-field cathodoluminescence of quantum dots. 2013 , 3, 062112		10
342	Automated in-chamber specimen coating for serial block-face electron microscopy. 2013 , 250, 101-110		28
341	Integration of a high-NA light microscope in a scanning electron microscope. 2013 , 252, 58-70		68
	Specifications for hard condensed matter specimens for three-dimensional high-resolution		
340	tomographies. <i>Microscopy and Microanalysis</i> , 2013 , 19, 726-39	0.5	17
340		0.5	17
	Atomic Resolution Secondary Electron Imaging with Aberration Corrected Scanning Transmission	0.5	17
339	Atomic Resolution Secondary Electron Imaging with Aberration Corrected Scanning Transmission Electron Microscope. 2013 , 34, 247-252 Quantitative Cathodoluminescence Opens New Areas of Investigation in Semiconductor Research		4
339	Atomic Resolution Secondary Electron Imaging with Aberration Corrected Scanning Transmission Electron Microscope. 2013, 34, 247-252 Quantitative Cathodoluminescence Opens New Areas of Investigation in Semiconductor Research and Production. 2013, 21, 34-38 Characterisation of rare earth minerals with field emission scanning electron microscopy. 2013, 52, 329-3 Beam-induced motion of adatoms in the transmission electron microscope. <i>Microscopy and</i>		
339 338 337	Atomic Resolution Secondary Electron Imaging with Aberration Corrected Scanning Transmission Electron Microscope. 2013, 34, 247-252 Quantitative Cathodoluminescence Opens New Areas of Investigation in Semiconductor Research and Production. 2013, 21, 34-38 Characterisation of rare earth minerals with field emission scanning electron microscopy. 2013, 52, 329-3 Beam-induced motion of adatoms in the transmission electron microscope. <i>Microscopy and</i>	334	4
339 338 337 336	Atomic Resolution Secondary Electron Imaging with Aberration Corrected Scanning Transmission Electron Microscope. 2013, 34, 247-252 Quantitative Cathodoluminescence Opens New Areas of Investigation in Semiconductor Research and Production. 2013, 21, 34-38 Characterisation of rare earth minerals with field emission scanning electron microscopy. 2013, 52, 329-3 Beam-induced motion of adatoms in the transmission electron microscope. <i>Microscopy and Microanalysis</i> , 2013, 19, 479-86 Environmental Scanning Ultrafast Electron Microscopy: Structural Dynamics of Solvation at Interfaces. 2013, 125, 2969-2973 Dark-field imaging of thin specimens with a forescatter electron detector at low accelerating	334	4 38
339 338 337 336 335	Atomic Resolution Secondary Electron Imaging with Aberration Corrected Scanning Transmission Electron Microscope. 2013, 34, 247-252 Quantitative Cathodoluminescence Opens New Areas of Investigation in Semiconductor Research and Production. 2013, 21, 34-38 Characterisation of rare earth minerals with field emission scanning electron microscopy. 2013, 52, 329-3 Beam-induced motion of adatoms in the transmission electron microscope. Microscopy and Microanalysis, 2013, 19, 479-86 Environmental Scanning Ultrafast Electron Microscopy: Structural Dynamics of Solvation at Interfaces. 2013, 125, 2969-2973 Dark-field imaging of thin specimens with a forescatter electron detector at low accelerating	334	4 38

331	Automated robotic assembly for a micro-cartridge system inside the scanning electron microscope. 2014 ,		3
330	Duplex Surface Treatment IPhysical Vapor Deposition (PVD) and Subsequent Electron Beam Hardening (EBH). 2014 , 16, 511-516		18
329	Visualization of carrier dynamics in $p(n)$ -type GaAs by scanning ultrafast electron microscopy. 2014 , 111, 2094-9		38
328	Improving scanning electron microscope resolution for near planar samples through the use of image restoration. <i>Microscopy and Microanalysis</i> , 2014 , 20, 78-89	0.5	8
327	Optimizing annular semiconductor detectors of back scattered electrons in SEM. 2014 , 78, 839-845		3
326	Optical system for a multiple-beam scanning electron microscope. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2014 , 32, 051801	1.3	5
325	On secondary electron emission and its semi-empirical description. 2014 , 56, 123002		22
324	Focal depth measurement of scanning helium ion microscope. 2014 , 105, 023105		7
323	Simultaneous imaging of the ferromagnetic and ferroelectric structure in multiferroic heterostructures. 2014 , 2, 076109		18
322	Scanning electron microscope image signal-to-noise ratio monitoring for micro-nanomanipulation. 2014 , 36, 419-29		14
321	Influence of an Electron Beam Exposure on the Surface Plasmon Resonance of Gold Nanoparticles. 2014 , 9, 343-348		1
320	Improved identification of transition metals in airborne aerosols by SEM-EDX combined backscattered and secondary electron microanalysis. 2014 , 21, 4023-31		10
319	Backscattered electron SEM imaging of cells and determination of the information depth. 2014 , 254, 75-83		9
318	Cross-sectional atomic force microscope in scanning electron microscope. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2014 , 32, 06FC04	1.3	1
317	Ionic liquid-based observation technique for nonconductive materials in the scanning electron microscope: Application to the characterization of a rare earth ore. 2014 , 77, 225-35		8
316	Backscattered electron imaging of micro- and nanostructures: 1. Method of analysis. <i>Journal of Surface Investigation</i> , 2014 , 8, 775-786	0.5	9
315	SEM characterization of carbon nanotubes based active layers of chemical sensors. 2014,		
314	Exploring structural similarities between crystal phases using EBSD pattern comparison. 2014 , 49, 490-	501	12

313	Electron Probe Techniques. 2014, 709-740		1
312	Sample thickness determination by scanning transmission electron microscopy at low electron energies. <i>Microscopy and Microanalysis</i> , 2014 , 20, 111-23	0.5	14
311	Introduction to Surface and Interface Analysis. 2014 , 78, 401-407		2
310	Nanometer-scale Real-space Observation and Material Processing for Polymer Materials under Atmospheric Pressure: Application of Atmospheric Scanning Electron Microscopy. 2014 , 82, 359-363		5
309	SEM, TEM and SLEEM (scanning low energy electron microscopy) of CB2 steel after creep testing. 2014 , 55, 012008		3
308	SEM and TEM Characterization of Polymer CNT Nanocomposites. 2014 , 167-185		2
307	Influence of primary electron energy and take-off angle of scanning electron microscopy on backscattered electron contrast of iron oxide. 2014 , 46, 1291-1295		7
306	Corrosive Degeneration of Autoclaves for the Ammonothermal Synthesis: Experimental Approach and First Results. 2014 , 37, 1903-1906		9
305	Improvement of CD-SEM mark position measurement accuracy. 2014,		
304	A compact physical CD-SEM simulator for IC photolithography modeling applications. 2014 ,		
303	Combined scanning transmission electron microscopy tilt- and focal series. <i>Microscopy and Microanalysis</i> , 2014 , 20, 548-60	0.5	20
302	CD-SEM metrology for sub-10nm width features. 2014 ,		10
301	Investigation of interactions between metrology and lithography with a CD SEM simulator. 2014,		2
300	On the Calculation of SEM and FIB Beam Profiles. <i>Microscopy and Microanalysis</i> , 2015 , 21, 206-211	0.5	3
299	Multiple-Beam Scanning Electron Microscopy. 2015 , 23, 12-19		14
298	Semiconductor detectors of backscattered electrons in a scanning electron microscope: Characteristics and applications. 2015 , 58, 757-764		4
297	Analysis of improvement in performance and design parameters for enhancing resolution in an atmospheric scanning electron microscope. <i>Microscopy (Oxford, England)</i> , 2015 , 64, 449-54	1.3	

(2015-2015)

295	Backscattered electron imaging of micro- and nanostructures: 2. Rectangular structures. <i>Journal of Surface Investigation</i> , 2015 , 9, 496-507	0.5	9
294	Backscattered electron imaging of microand nanostructures: 3. Structures with a trapezoidal profile and small side-wall inclination angles. <i>Journal of Surface Investigation</i> , 2015 , 9, 1060-1069	0.5	9
293	Low-energy scanning electron microscope using a monochromator with double-offset cylindrical lenses. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2015 , 33, 06FJ	104	4
292	Evaluation of Material Parameters of Multiphase Materials Using Drift Distortion Corrected SEM Imaging. 2015 , 662, 253-256		
291	Efficient cross-section preparation method for high-resolution imaging of hard polymer composites with a scanning electron microscope. 2015 , 260, 117-24		6
2 90	Calculation of Bohmian quantum trajectories for STEM. 2015 , 260, 200-7		6
289	Electron Microscopic Techniques for Surface Analysis of Steel Products. 2015 , 64, 381-387		
288	Ultra-High-Resolution Observation and Analysis Using Field-Emission Scanning Electron Microscope. 2015 , 66, 577-580		
287	Monte Carlo study of the effective electron beam shape in scanning electron microscopic imaging. 2015 , 69, 30703		7
286	Microscopy. 2015 , 1-20		
285	Secondary electron imaging of monolayer materials inside a transmission electron microscope. 2015 , 107, 063105		3
284	Error analysis of the crystal orientations and disorientations obtained by the classical electron backscatter diffraction technique. 2015 , 48, 797-813		37
283	Understanding the impact of CD-SEM artifacts on metrology via experiments and simulations. 2015		
282	Dual-phase steel structure visualized by extremely slow electrons. <i>Microscopy (Oxford, England)</i> , 2015 , 64, 437-43	1.3	4
281	Characterization of complex phase steel using backscattered electron images with controlled collection angles. <i>Microscopy (Oxford, England)</i> , 2015 , 64, 297-304	1.3	7
280	Quantum-trajectory Monte Carlo method for study of electron-crystal interaction in STEM. 2015 , 17, 17628-37		10
279	In situ observation of water in a fuel cell catalyst using scanning electron microscopy. <i>Microscopy</i> (Oxford, England), 2015 , 64, 87-96	1.3	4
278	Scanning electron microscope hypsometry as a tool for evaluating the impact of surface treatments: A case study on sub-fossil bone. 2015 , 60, 55-64		O

277	Surface modification of multilayer graphene using Ga ion irradiation. 2015 , 117, 165303		11
276	Mesoporous Siloxane Films Through Thermal Oxidation of Siloxane arbon Nanocomposites. 2015 , 17, 1547-1555		5
275	Scanning electron microscopy imaging mechanisms of CVD-grown graphene on Cu substrate revealed by in situ observation. 2015 , 54, 050301		4
274	Local variations of HER2 dimerization in breast cancer cells discovered by correlative fluorescence and liquid electron microscopy. 2015 , 1, e1500165		65
273	Quantitative analysis of angle-selective backscattering electron image of iron oxide and steel. <i>Microscopy (Oxford, England)</i> , 2015 , 64, 319-25	1.3	7
272	Kikuchi pattern analysis of noncentrosymmetric crystals. 2015 , 48, 1405-1419		23
271	Microstructural evolution in a Ti T a high-temperature shape memory alloy during creep. 2015 , 106, 331-341		8
270	Real-Space Imaging of Carrier Dynamics of Materials Surfaces by Second-Generation Four-Dimensional Scanning Ultrafast Electron Microscopy. 2015 , 6, 3884-90		31
269	Electron Probe Measurements of Oxide Film Thickness on Silicon Surfaces. 2015 , 58, 953-957		1
268	Electron microscopy of quantum dots. 2015 , 257, 171-8		6
267	Improved spectrum simulation for validating SEM-EDS analysis. 2016 , 109, 012016		3
266	Experimental determination of electron-beam broadening in low-energy STEM. 2016 , 525-526		
265	Composition quantification of thin samples by backscattered electron imaging in scanning electron microscopy. 2016 , 535-536		
264	Characterization Techniques for Film Characteristics. 2016 , 123-158		
263	Secondary Electron Emission of Pt: Experimental Study and Comparison With Models in the Multipactor Energy Range. 2016 , 63, 3270-3277		9
262	Transmission electron imaging in the Delft multibeam scanning electron microscope 1. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2016 , 34, 06KF02	1.3	7
261	Brightness measurement of an electron impact gas ion source for proton beam writing applications. 2016 , 87, 02A903		7
260	On a hyperbolic conservation law of electron transport in solid materials for electron probe microanalysis. 2016 , 47, 575-588		3

259	Non-destructive electron microscopy imaging and analysis of biological samples with graphene coating. <i>2D Materials</i> , 2016 , 3, 045004	5.9	23
258	A comparison on absorption coefficients for secondary electron emission obtained from two different formulas. <i>Moscow University Physics Bulletin (English Translation of Vestnik Moskovskogo Universiteta, Fizika</i>), 2016 , 71, 420-430	0.7	O
257	Distinction between amorphous and healed planar deformation features in shocked quartz using composite color scanning electron microscope cathodoluminescence (SEM-CL) imaging. 2016 , 51, 1914-	1931	6
256	Characterization of Amorphous Oxide Nano-Thick Layers on 316L Stainless Steel by Electron Channeling Contrast Imaging and Electron Backscatter Diffraction. <i>Microscopy and Microanalysis</i> , 2016 , 22, 997-1006	0.5	9
255	The New Methodology and Chemical Contrast Observation by Use of the Energy-Selective Back-Scattered Electron Detector. <i>Microscopy and Microanalysis</i> , 2016 , 22, 1369-1373	0.5	8
254	Spatial Resolution in Scanning Electron Microscopy and Scanning Transmission Electron Microscopy Without a Specimen Vacuum Chamber. <i>Microscopy and Microanalysis</i> , 2016 , 22, 754-67	0.5	4
253	Physics-based simulation models for EBSD: advances and challenges. 2016 , 109, 012018		14
252	Surface sensitivity of secondary electrons emitted from amorphous solids: Calculation of mean escape depth by a Monte Carlo method. 2016 , 120, 235102		20
251	Real-Space Mapping of Surface Trap States in CIGSe Nanocrystals Using 4D Electron Microscopy. 2016 , 16, 4417-23		20
250	Image Contrast in Energy-Filtered BSE Images at Ultra-Low Accelerating Voltages. 2016 , 24, 20-25		1
249	Gaining insight into effective metrology height through the use of a compact CDSEM model for lithography simulation. 2016 ,		2
248	On Rotation Contour Contrast in Hot-Compressed Magnesium Alloys in a Scanning Electron Microscope. 2016 , 5, 188-195		1
247	An EBIC Model for TCAD Simulation to Determine the Surface Recombination Rate in Semiconductor Devices. 2016 , 63, 4395-4401		3
246	Wafer-scale automation of electron beam induced depositions. 2016,		1
245	Nail Damage (Severe Onychodystrophy) Induced by Acrylate Glue: Scanning Electron Microscopy and Energy Dispersive X-Ray Investigations. 2017 , 2, 137-142		4
244	Particle Number Size Distribution. 2016 , 63-80		
243	Backscattered electron imaging of micro- and nanostructures: 5. SEM signal formation model. Journal of Surface Investigation, 2016 , 10, 892-905	0.5	7
242	Information or resolution: Which is required from an SEM to study bulk inorganic materials?. 2016 , 38, 864-879		6

241	A Large-Area Transferable Wide Band Gap 2D Silicon Dioxide Layer. 2016 , 10, 7982-9		37
240	Electrical conductivity of a silicone network upon electron irradiation: influence of formulation. 2016 , 49, 505303		7
239	Plasmon resonant (e, 2e) spectroscopy on Be(0001). 2016 , 94,		3
238	Site-Specific Preparation of Intact Solid-Liquid Interfaces by Label-Free In Situ Localization and Cryo-Focused Ion Beam Lift-Out. <i>Microscopy and Microanalysis</i> , 2016 , 22, 1338-1349	0.5	26
237	Laser-induced asymmetric faceting and growth of a nano-protrusion on a tungsten tip. 2016 , 1, 091305		7
236	Backscattered electron imaging of microand nanostructures: 4. Structures with a trapezoidal profile and large side-wall inclination angles. <i>Journal of Surface Investigation</i> , 2016 , 10, 221-230	0.5	7
235	Exposure and analysis of microparticles embedded in silica aerogel keystones using NF3-mediated electron beaminduced etching and energy-dispersive X-ray spectroscopy. 2016 , 51, 1223-1232		
234	Supramolecular Structure and Mechanical Characteristics of Ultrahigh-Molecular-Weight PolyethyleneIhorganic Nanoparticle Nanocomposites. 2016 , 37, 439-444		5
233	Computation in electron microscopy. 2016 , 72, 1-27		24
232	Comparison of technologies for nano device prototyping with a special focus on ion beams: A review. <i>Applied Physics Reviews</i> , 2017 , 4, 011302	17.3	37
		, ,	
231	Microstructure and Properties of Engineering Materials. 2017 , 1-20		8
231	Microstructure and Properties of Engineering Materials. 2017, 1-20 Secondary Electron Imaging of Light at the Nanoscale. 2017, 11, 3274-3281	, ,	5
230	Secondary Electron Imaging of Light at the Nanoscale. 2017 , 11, 3274-3281		5
230	Secondary Electron Imaging of Light at the Nanoscale. 2017 , 11, 3274-3281 About the information depth of backscattered electron imaging. 2017 , 266, 335-342		5
230 229 228	Secondary Electron Imaging of Light at the Nanoscale. 2017, 11, 3274-3281 About the information depth of backscattered electron imaging. 2017, 266, 335-342 Edge shadow projection method for measuring the brightness of electron guns. 2017, 88, 023302 Surface Characterization and Optical Study on Electrospun Nanofibers of PVDF/PAN Blends. 2017,		5 10 1
230 229 228 227	Secondary Electron Imaging of Light at the Nanoscale. 2017, 11, 3274-3281 About the information depth of backscattered electron imaging. 2017, 266, 335-342 Edge shadow projection method for measuring the brightness of electron guns. 2017, 88, 023302 Surface Characterization and Optical Study on Electrospun Nanofibers of PVDF/PAN Blends. 2017, 36, 78-90 Thermal Effects During Low-Voltage Electron-Probe X-Ray Spectral Microanalysis with Nanometer		5 10 1

223	Spatiotemporal Observation of Electron-Impact Dynamics in Photovoltaic Materials Using 4D Electron Microscopy. 2017 , 8, 2455-2462		12
222	Diffraction effects and inelastic electron transport in angle-resolved microscopic imaging applications. 2017 , 267, 330-346		12
221	The elusive ettringite under the high-vacuum SEM - a reflection based on natural samples, the use of Monte Carlo modelling of EDS analyses and an extension to the ettringite group minerals. 2017 , 268, 84-93		8
220	Cathodoluminescence studies of defects in coated boron nitride. 2017 , 50, 295302		1
219	Crystallometric and projective properties of Kikuchi diffraction patterns. 2017, 50, 102-119		11
218	Three-dimensional cathodoluminescence characterization of a semipolar GaInN based LED sample. 2017 , 121, 075702		5
217	Electron backscatter diffraction beyond the mainstream. 2017 , 52, 1600252		32
216	Optoelectronic Properties of PCPDTBT for Photovoltaics: Morphology Control and Molecular Doping. 2017 , 109-138		2
215	Focused electron beam based direct-write fabrication of graphene and amorphous carbon from oxo-functionalized graphene on silicon dioxide. 2017 , 19, 2683-2686		3
214	Transformation of ACC into aragonite and the origin of the nanogranular structure of nacre. 2017 , 7, 12728		20
214			20
	7, 12728	0.5	20
213	7, 12728 Characterization Using Passive or Interactive Techniques. 2017, 35-256 Monte Carlo method in scanning electron microscopy. 1. Modeling and experiment. <i>Journal of</i>	0.5	
213	7, 12728 Characterization Using Passive or Interactive Techniques. 2017, 35-256 Monte Carlo method in scanning electron microscopy. 1. Modeling and experiment. <i>Journal of Surface Investigation</i> , 2017, 11, 853-864 Tuning the Band Gap in Titanium Dioxide Thin Films by Surfactant-Mediated Confinement and	0.5	6
213	Characterization Using Passive or Interactive Techniques. 2017, 35-256 Monte Carlo method in scanning electron microscopy. 1. Modeling and experiment. <i>Journal of Surface Investigation</i> , 2017, 11, 853-864 Tuning the Band Gap in Titanium Dioxide Thin Films by Surfactant-Mediated Confinement and Patterning of Gold Nanoparticles. 2017, 121, 21311-21323 The structure and phase composition of hard alloys of the Cr3C2-Ti system produced by explosive	0.5	6
213 212 211 210	Characterization Using Passive or Interactive Techniques. 2017, 35-256 Monte Carlo method in scanning electron microscopy. 1. Modeling and experiment. <i>Journal of Surface Investigation</i> , 2017, 11, 853-864 Tuning the Band Gap in Titanium Dioxide Thin Films by Surfactant-Mediated Confinement and Patterning of Gold Nanoparticles. 2017, 121, 21311-21323 The structure and phase composition of hard alloys of the Cr3C2-Ti system produced by explosive compacting of powders. 2017, 177, 012109 Enhanced flexibility and electron-beam-controlled shape recovery in alumina-coated Au and Ag	0.5	6
213 212 211 210 209	Characterization Using Passive or Interactive Techniques. 2017, 35-256 Monte Carlo method in scanning electron microscopy. 1. Modeling and experiment. Journal of Surface Investigation, 2017, 11, 853-864 Tuning the Band Gap in Titanium Dioxide Thin Films by Surfactant-Mediated Confinement and Patterning of Gold Nanoparticles. 2017, 121, 21311-21323 The structure and phase composition of hard alloys of the Cr3C2-Ti system produced by explosive compacting of powders. 2017, 177, 012109 Enhanced flexibility and electron-beam-controlled shape recovery in alumina-coated Au and Ag core-shell nanowires. 2017, 28, 505707	0.5	6 6 11

205	Enhanced Imaging of Lithium Ion Battery Electrode Materials. 2017, 164, A6032-A6038		16
204	Thermal Action of an Electronic Probe with X-ray Spectral Nanoanalysis. 2017 , 60, 534-537		6
203	Multi template matching-based drift compensation for electron beam induced deposition. 2017,		O
202	Low-Voltage Scanning Electron Microscopy as a Tool for Surface Imaging and Analysis of Practical Materials. 2017 , 24, 129-135		3
201	Electron beam induced deposition of silacyclohexane and dichlorosilacyclohexane: the role of dissociative ionization and dissociative electron attachment in the deposition process. 2017 , 8, 2376-23	88	1
200	Microscopy Electron Microscopy. 2017 , 19-19		
199	A deterministic model of electron transport for electron probe microanalysis. 2018 , 304, 012004		5
198	Observation of dynamical crater-shaped charge distribution in the space-time imaging of monolayer graphene. 2018 , 10, 10343-10350		3
197	Lateral sensitivity in electron probe microanalysis studied by Monte Carlo simulations involving fluorescence enhancements. 2018 , 270, 136-141		
196	Exploring the Influence of a Focusing and Gaussian Profile Electron Beam in SEM Imaging through Monte Carlo Simulation. <i>Moscow University Physics Bulletin (English Translation of Vestnik Moskovskogo Universiteta, Fizika</i>), 2018 , 73, 89-94	0.7	5
195	A Monte Carlo modeling on charging effect for structures with arbitrary geometries. 2018 , 51, 165301		13
194	In lens BSE detector with energy filtering. <i>Ultramicroscopy</i> , 2018 , 189, 102-108	3.1	3
193	On the Progress of Scanning Transmission Electron Microscopy (STEM) Imaging in a Scanning Electron Microscope. <i>Microscopy and Microanalysis</i> , 2018 , 24, 99-106	0.5	20
192	Recent Developments of Crystallographic Analysis Methods in the Scanning Electron Microscope for Applications in Metallurgy. 2018 , 43, 455-474		22
191	Enhanced EDX images by fusion of multimodal SEM images using pansharpening techniques. 2018 , 269, 94-112		1
190	Synthesis and characterization of Titanium Silicon Nitride (TiSiN) thin film: A review. 2018 , 377, 012181		3
189	Multi-Beam Scanning Electron Microscopy for High-Throughput Imaging in Connectomics Research. 2018 , 12, 112		21
188	Cathodoluminescence spectroscopy for failure analysis and process development of GaN-based microelectronic devices. 2018 ,		

187	Size limits of magnetic-domain engineering in continuous in-plane exchange-bias prototype films. 2018 , 9, 2968-2979		8
186	Monte Carlo Method in Scanning Electron Microscopy. 3. Modern Condition of the Problem. <i>Journal of Surface Investigation</i> , 2018 , 12, 460-465	0.5	1
185	Contrast Formation in the SEM. 2018 , 77-128		2
184	Imaging with the SEM. 2018 , 129-180		О
183	Characteristics of X-Rays. 2018, 233-264		
182	Luminescence methodology to determine grain-boundary, grain-interior, and surface recombination in thin-film solar cells. 2018 , 124, 113104		16
181	Metallization defect detection in 3D integrated components using scanning acoustic microscopy and acoustic simulations. 2018 , 88-90, 262-266		1
180	Low-voltage SEM contrasts of steel surface studied by observations and electron trajectory simulations for GEMINI lens system. <i>Microscopy (Oxford, England)</i> , 2018 , 67, 274-279	1.3	2
179	First-Surface Scintillator for Low Accelerating Voltage Scanning Electron Microscopy (SEM) Imaging. <i>Microscopy and Microanalysis</i> , 2018 , 24, 488-496	0.5	2
178	STEM Imaging with Beam-Induced Hole and Secondary Electron Currents. <i>Physical Review Applied</i> , 2018 , 10,	4.3	21
177	Monte Carlo calculation of the backscattering coefficient of thin films of low on high atomic number materials and the reverse as a function of the incident electron energy and film thickness. 2018 , 124, 1		2
176	The Determination and Application of the Point Spread Function in the Scanning Electron Microscope. <i>Microscopy and Microanalysis</i> , 2018 , 24, 396-405	0.5	5
175	Investigating Contact Phenomena at a PZTPt Interface by Means of Induced Current. 2018, 82, 338-340		
174	Monte Carlo Method in Scanning Electron Microscopy. 2. Problems and Solutions. <i>Journal of Surface Investigation</i> , 2018 , 12, 179-184	0.5	2
173	High charge density silica micro-electrets fabricated by electron beam. 2018 , 27, 075052		1
172	New attempt to combine scanning electron microscopy and small-angle scattering in reciprocal space. 2019 , 52, 783-790		2
171	Imaging and Mapping Characterization Tools for Perovskite Solar Cells. 2019 , 9, 1900444		27
170	Electron-beam enhanced creep deformation of amorphous silicon nano-cantilever. 2019 , 126, 105102		3

169	Formation of SEM Images in the Slow Secondary Electron Mode. 1. Structures with Large Side Wall Inclinations. <i>Journal of Surface Investigation</i> , 2019 , 13, 727-733	0.5	O
168	Depth-correlated backscattered electron signal intensity for 3D-profile measurement of high aspect ratio holes. <i>Microscopy (Oxford, England)</i> , 2019 , 68, 385-394	1.3	O
167	High-resolution hard-x-ray photoelectron diffraction in a momentum microscope E he model case of graphite. 2019 , 21, 113031		12
166	X-Ray Spectroscopy for Electrostatic Potential and Material Determination of Space Objects. 2019 , 47, 3858-3866		13
165	Scanning transmission electron microscope mapping of electronic transport in polycrystalline BaTiO3 ceramic capacitors. 2019 , 115, 133502		12
164	CIRP Encyclopedia of Production Engineering. 2019 , 1501-1505		O
163	Estimating Step Heights from Top-Down SEM Images. <i>Microscopy and Microanalysis</i> , 2019 , 25, 903-911	0.5	1
162	Graphene to graphene, and substrate to substrate: how to reliably differentiate supported graphene from polycrystalline substrates using SEM?. 2019 , 6, 085604		3
161	Direct growth of graphene-like film microstructure on charge pre-patterned SiO2/Si substrate. 2019 , 30, 10639-10643		2
160	Analysis of micro and nano particle erosion by analytical, numerical and experimental methods: A review. 2019 , 33, 2319-2329		6
159	Impact of Electron-Beam Heating during 3D Nanoprinting. 2019 , 13, 5198-5213		26
158	Constraints on the effective electron energy spectrum in backscatter Kikuchi diffraction. 2019 , 99,		11
157	High-Resolution Cryo-Scanning Electron Microscopy of Macromolecular Complexes. 2019 , 265-297		1
156	SBEM Techniques. 2019 , 495-516		
155	Backscattered electron detector for 3D microstructure visualization in scanning electron microscopy. 2019 , 90, 023701		4
154	Three-dimensional Structure Recognition of Circuit Patterns on Semiconductor Devices Using Multiple SEM Images Detected in Different Electron Scattering Angles. 2019 ,		
153	Application of magnetic field for improvement of energy spread of an electron beam. 2019 , 1380, 0120	05	
152	Formation of SEM Images in the Secondary Electron Mode. 2. Structures with a Trapezoidal Profile and Small Side-Wall Inclinations. <i>Journal of Surface Investigation</i> , 2019 , 13, 972-978	0.5	

151	Cathodoluminescence of aluminum ceramic compounds. 2019 , 125, 025110	4
150	Influence of nucleating agent type on the morphology of extruded polyetherimide foam for printed circuit boards*. 2020 , 56, 317-341	2
149	A comparative study on Monte Carlo simulations of electron emission from liquid water. 2020 , 47, 759-771	14
148	Quantitative Nanoscale Absorption Mapping: A Novel Technique To Probe Optical Absorption of Two-Dimensional Materials. 2020 , 20, 567-576	10
147	In Operando Monitoring by Analysis of Backscattered Electrons during Electron Beam Melting. 2020 , 22, 1901102	4
146	Characterization of ferroelectric domain walls by scanning electron microscopy. 2020 , 128, 191102	7
145	Magnetic bottle electron spectrometer driven by electron pulses. 2020 , 91, 073108	
144	Refined Calibration Model for Improving the Orientation Precision of Electron Backscatter Diffraction Maps. 2020 , 13,	11
143	. 2020 , 20, 14218-14227	9
142	Advances in electron channelling contrast imaging and electron backscatter diffraction for imaging and analysis of structural defects in the scanning electron microscope. 2020 , 891, 012023	
141	Improving the Energy Resolution of Energy Dispersive Spectrometers(EDS) Using Richardson Deconvolution. <i>Microscopy and Microanalysis</i> , 2020 , 26, 1210-1211	
140	Experimental Investigation of the Secondary and Backscatter Electron Emission from Spacecraft Materials. 2020 , 57, 793-808	O
139	Application of the rolling ball algorithm to measure phase volume fraction from backscattered electron images. 2020 , 163, 110273	3
138	Ammonia and phosphorus removal from agricultural runoff using cash crop waste-derived biochars. 2020 , 14, 1	11
137	Momentum-transfer model of valence-band photoelectron diffraction. 2020 , 3,	9
136	Electron-beam irradiation alters bond strength in zinc oxide single crystal. 2020 , 116, 111902	5
135	STEM EBIC for High-Resolution Electronic Characterization. 2020,	1
134	Structural and luminescence imaging and characterisation of semiconductors in the scanning electron microscope. 2020 , 35, 054001	3

133	The matrix effect in TOF-SIMS analysis of two-element inorganic thin films. 2020, 35, 1156-1166		17
132	Test Objects with a Rectangular Profile for SEM: 2. Certification of the Groove Width. <i>Journal of Surface Investigation</i> , 2020 , 14, 105-116	0.5	1
131	An introduction to cryo-FIB-SEM cross-sectioning of frozen, hydrated Life Science samples. 2021 , 281, 138-156		11
130	Microstructural development of vanadiumflickel crystalline alloy membranes. 2021 , 40, 1932-1939		O
129	Phase plates in the transmission electron microscope: operating principles and applications. <i>Microscopy (Oxford, England)</i> , 2021 , 70, 75-115	1.3	8
128	Ultrathin Porous Hydrocarbon Membranes Templated by Nanoparticle Assemblies. 2021 , 21, 166-174		O
127	Overview of S(T)EM electron detectors with garnet scintillators: Some potentials and limits. 2021 , 84, 753-770		2
126	Atomic Structure and Microstructure Characterization. 2021 , 131-163		
125	A Review of the Microstructural Location of Impurities in Polar Ice and Their Impacts on Deformation. 2021 , 8,		4
124	Damage-less observation of polymers by electron dose control in scanning electron microscope. <i>Microscopy (Oxford, England)</i> , 2021 , 70, 375-381	1.3	1
123	Electron probe microanalysis: A review of recent developments and applications in materials science and engineering. 2021 , 116, 100673		16
122	Extending Cryo-EM to Nonaqueous Liquid Systems. 2021 , 54, 2100-2109		6
121	Analytical Cryo-Scanning Electron Microscopy of Hydrated Polymers and Microgels. 2021 , 54, 2386-239	6	4
120	Scanning Electron Microscopy versus Transmission Electron Microscopy for Material Characterization: A Comparative Study on High-Strength Steels. 2021 , 2021, 5511618		2
119	Calibration of a Scanning Electron Microscope: 1. Selection of the SEM Parameters. <i>Journal of Surface Investigation</i> , 2021 , 15, 502-512	0.5	1
118	Crystallographic analysis of the lattice metric () from single electron backscatter diffraction or transmission Kikuchi diffraction patterns. 2021 , 54, 1012-1022		1
117	Employing Cathodoluminescence for Nanothermometry and Thermal Transport Measurements in Semiconductor Nanowires. 2021 ,		4
116	Thermal conductance at Sn-0.5mass%Al solder alloy/substrate interface as a factor for tailoring cellular/dendritic growth. 1		1

115	Reprint of: Electron probe microanalysis: A review of recent developments and applications in materials science and engineering. 2021 , 120, 100818		1
114	Use of spectrum simulation to optimise collection parameters for accurate and efficient WDS and EDS quantitative analyses. <i>Microscopy and Microanalysis</i> , 2021 , 27, 1102-1104	0.5	
113	A Novel Reconstruction Method to Increase Spatial Resolution in Electron Probe Microanalysis. 2021 , 26, 51		
112	Quantification and Mitigation of Electron-Beam-Induced Carbon Contamination. <i>Microscopy and Microanalysis</i> , 2021 , 27, 2022-2024	0.5	
111	????????? 1.???? 1-3 ???????????? 1-3-1 ???????X????(EDS)???????. Materia Japan, 2021 , 60, 498-506	0.1	1
110	Effect of electron-irradiation on layered quantum materials. 2021 , 44, 1		2
109	Molecular Design, Synthesis, and Properties of Surface-Active Comb-Like PEG-Containing Polymers and Derived Supramolecular Structures for Drug Delivery. 2022 , 17-57		0
108	Microstructural Characterization of the Simulated Heat-Affected Zone of 9 Pct Ni Steel. 2021 , 52, 5016		1
107	Charging effect induced by electron beam irradiation: a review. 2021 , 22, 932-971		1
106	Reversible control of intrinsic shear strength of a ZnO single crystal through electron-beam-induced hole state. 2021 , 1		1
105	????????? 1.???? 1-3 ???????????? 1-3-2 ?????????(EBSD)????????? <i>Materia Japan</i> , 2021 , 60, 645-652	0.1	
104	Dynamical Simulation of Electron Backscatter Diffraction Patterns. 2009 , 21-33		12
103	Large-Scale Automated Serial Section Imaging with a Multibeam Scanning Electron Microscope. 2020 , 151-163		1
102	Cubic GaN on Nanopatterned 3C-SiC/Si (001) Substrates. Springer Series in Materials Science, 2013, 381-4	05 9	5
101	Scanning Electron Microscopy. 2019 , 229-318		13
100	AFM Sensors in Scanning Electron and Ion Microscopes: Tools for Nanomechanics, Nanoanalytics, and Nanofabrication. 2008 , 247-287		1
99	Emitter-site specificity of hard x-ray photoelectron Kikuchi-diffraction. 2020 , 22, 103002		8
98	Direct observation of recombination-enhanced dislocation glide in heteroepitaxial GaAs on silicon. 2018 , 2,		16

97	Electron-beam broadening in electron microscopy by solving the electron transport equation. 2020 , 2,		2
96	About the contrast of Ilprecipitates in bulk Al-Cu-Li alloys in reflection mode with a field-emission scanning electron microscope at low accelerating voltage. 2017 , 268, 107-118		7
95	Effect of Contamination on a Test Object for SEM Calibration. <i>Journal of Surface Investigation</i> , 2020 , 14, 1387-1393	0.5	2
94	Confirmation of tensile residual stress reduction in electron beam welding using low transformation temperature materials (LTT) as localized metallurgical injection Part 1: Metallographic analysis. 2017 , 59, 148-154		7
93	The Kinetics of Individual Grains in Polycrystalline Materials. 2012 , 49, 428-445		9
92	The application and limitations of the SEM-EDS method in food and textile technologies. 2017 , 6, 5-10		3
91	Photoresist Shrinkage Caused by Single-Line Scan of Electron Beam. 2012 , 51, 06FB10		2
90	Calibration of a Scanning Electron Microscope: 2. Methods of Signal Processing. <i>Journal of Surface Investigation</i> , 2021 , 15, 987-998	0.5	2
89	Mapping Charge Recombination and the Effect of Point-Defect Insertion in GaAs Nanowire Heterojunctions. <i>Physical Review Applied</i> , 2021 , 16,	4.3	
88	The Design of the Emission Layer for Electron Multipliers. 2021 , 16, 151		O
88 8 ₇	The Design of the Emission Layer for Electron Multipliers. 2021 , 16, 151 Electron Microscopy in Mineral Processing. 2002 ,		O
			O
87	Electron Microscopy in Mineral Processing. 2002,		O
8 ₇ 86	Electron Microscopy in Mineral Processing. 2002, Surfaces and Films. 2003, 756-790		0
8 ₇ 86 8 ₅	Electron Microscopy in Mineral Processing. 2002, Surfaces and Films. 2003, 756-790 Scanning Electron Microscopy. 2004, 355-367		
87 86 85 84	Electron Microscopy in Mineral Processing. 2002, Surfaces and Films. 2003, 756-790 Scanning Electron Microscopy. 2004, 355-367 Co-site Microscopy: Case Studies. 2009, 46, 483-498		
87 86 85 84 83	Electron Microscopy in Mineral Processing. 2002, Surfaces and Films. 2003, 756-790 Scanning Electron Microscopy. 2004, 355-367 Co-site Microscopy: Case Studies. 2009, 46, 483-498 References. 2009, 411-430 Selective Backscattered Electron Imaging of Material and Channeling Contrasts in Microstructures		1

79	References. 2011 , 407-436		
78	Measurement/Manipulation/Assembly of Carbon Nanotubes under FE-SEM/TEM. 2013 , 197-242		
77	CIRP Encyclopedia of Production Engineering. 2014 , 1085-1089		
76	Experimental Techniques. 1998 , 28-40		
75	Bibliography. 2014 , 243-249		
74	Encyclopedia of Nanotechnology. 2015 , 1-10		
73	Liquid Phase Experiments: Describing Experiments in Liquids and the Special Requirements and Considerations for Such Experiments. 2016 , 259-279		
72	Encyclopedia of Nanotechnology. 2016 , 3499-3507		
71	Scanning Electron Microscope. 2017 , 1-5		
70	Electron Diffraction Techniques in the SEM. SpringerBriefs in Applied Sciences and Technology, 2018, 85	5-1 05 4	
69	Advanced Specimen Preparation. SpringerBriefs in Applied Sciences and Technology, 2018, 115-128	0.4	О
68	Introduction. SpringerBriefs in Applied Sciences and Technology, 2018, 1-4	0.4	1
67	X-Ray Imaging with a Silicon Drift Detector Energy Dispersive Spectrometer. <i>SpringerBriefs in Applied Sciences and Technology</i> , 2018 , 67-84	0.4	
66	Low Voltage STEM in the SEM. SpringerBriefs in Applied Sciences and Technology, 2018 , 47-53	0.4	
65	Low Voltage SEM. SpringerBriefs in Applied Sciences and Technology, 2018, 37-46	0.4	О
64	Magnetic Domain Imaging. SpringerBriefs in Applied Sciences and Technology, 2018, 107-113	0.4	
63	Electron Detection Strategies for High Resolution Imaging: Deceleration and Energy Filtration. <i>SpringerBriefs in Applied Sciences and Technology</i> , 2018 , 13-35	0.4	
62	Developments in Field Emission Gun Technologies and Advanced Detection Systems. <i>SpringerBriefs in Applied Sciences and Technology</i> , 2018 , 5-12	0.4	1

61	Development of a secondary electron energy analyzer for a transmission electron microscope. <i>Microscopy (Oxford, England)</i> , 2018 , 67, 121-124	1.3	
60	Scanning Electron Microscopy. 2018 , 563-569		
59	Model improvements to simulate charging in SEM. 2018,		
58	Principles and Practice of Metallography. <i>Cultural Heritage Science</i> , 2019 , 19-68	1.4	
57	An Introduction to Instrumentation Used in Fire Debris and Explosive Analysis. 2019, 1-43		0
56	Imaging Methods. Springer Series in Measurement Science and Technology, 2019 , 199-217	0.3	
55	Untersuchungsmethoden der Mikrostruktur. 2019 , 211-235		
54	Focused Ion Beam Instruments. 2019 , 635-670		
53	Introduction. Nanoscience and Technology, 2019 , 1-13	0.6	
52	A programmable dark-field detector for imaging two-dimensional materials in the scanning electron microscope. 2019 ,		
51	Cathodes for Electron Microscopy and Lithography. <i>Topics in Applied Physics</i> , 2020 , 251-292	0.5	1
50	Investigation and Discovery of the Integration of FEOL Process by Electron Beam Inspections. 2020,		
49	Study of Reversal Contrast Phenomenon in SEM Images at Low Incident Accelerating Voltage by AES. <i>Vacuum and Surface Science</i> , 2020 , 63, 294-297	О	
48	Design of an efficient collector for the HIAF electron cooling system. <i>Nuclear Science and Techniques/Hewuli</i> , 2021 , 32, 1	2.1	2
47	In Situ Techniques for Characterization of Strain Localizations and Time Sequence of Deformation Processes. <i>Springer Series in Materials Science</i> , 2020 , 99-203	0.9	
46	The Importance of Nano-materials Characterization Techniques. Engineering Materials, 2020, 19-37	0.4	
45	Bismuth Ferrites: Synthesis Methods and Experimental Techniques. <i>SpringerBriefs in Materials</i> , 2020 , 47-67	0.5	1
44	Three-Dimensional Scanning Electron Microscopy of Surface Topography with Consideration of the Effect of the Response Function of the Detector System. <i>Moscow University Physics Bulletin (English Translation of Vestnik Moskovskogo Universiteta, Fizika</i>), 2021 , 76, 209-214	0.7	

43 Materials Characterization Techniques for Solar Cell Devices. 294-307

42	Materials Characterization Techniques for Solar Cell Devices. 1181-1194		
41	Low energy scanning analytical microscopy (LeSAM) for Auger and low voltage SEM imaging of semiconductors. 2005 , 499-502		
40	Nanostructuring and Nanobonding by EBiD. 2008 , 295-340		1
39	3D Imaging System for SEM. 2008 , 129-165		
38	An Improved Method to Detect Riblets on Surfaces in Nanometer Scaling Using SEM. 2008 , 43-54		
37	Test Objects with a Rectangular Profile for SEM: 3. Coordinate Measurements on a SEM. <i>Journal of Surface Investigation</i> , 2020 , 14, 965-977	0.5	О
36	Multiple criteria optimization of electrostatic electron lenses using multiobjective genetic algorithms. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2021 , 39, 062605	1.3	
35	????????? 1.???? 1-3 ???????????? 1-3-2 ?????????(EBSD)????????(??). Materia Japan, 2021 , 60, 793-799	0.1	
34	Diffusion of zirconium on the surface of Schottky electron sources. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2021 , 39, 062806	1.3	
33	Touchless Potential Sensing of Complex Differentially-Charged Shapes Using X-Rays. 2022,		0
32	Carrier Diffusion in GaN: A Cathodoluminescence Study. I. Temperature-Dependent Generation Volume. <i>Physical Review Applied</i> , 2022 , 17,	4.3	2
31	A New Scenario for the Kinetics of Charging Dielectrics under Irradiation with Medium-Energy Electrons. <i>Physics of the Solid State</i> , 2021 , 63, 628-643	0.8	2
30	Non-Destructive Detection of Buried and Latent Defects by Negative Mode E-Beam Inspection. <i>IEEE Transactions on Semiconductor Manufacturing</i> , 2022 , 1-1	2.6	O
29	A Novel Monochromator with Offset Cylindrical Lenses and Its Application to a Low-Voltage Scanning Electron Microscope <i>Microscopy and Microanalysis</i> , 2022 , 1-13	0.5	O
28	Synthesis, Characterization and Application of AlTiZrO4 Nanomaterial. <i>International Journal of Advanced Research in Science, Communication and Technology</i> , 57-65	0.5	
27	ESEM Methodology for the Study of Ice Samples at Environmentally Relevant Subzero Temperatures: "Subzero ESEM" <i>Microscopy and Microanalysis</i> , 2021 , 1-14	0.5	О
26	Quantification of STEM Images in High Resolution SEM for Segmented and Pixelated Detectors <i>Nanomaterials</i> , 2021 , 12,	5.4	

Portable Nanomaterials Impregnated Paper-Based Sensors for Detection of Chemical Substances. **2022**, 21-47

24	Charging characteristics of LiTaO3 crystals under irradiation with defocused electron beams of various energies. <i>Ferroelectrics</i> , 2021 , 585, 25-39	0.6	2
23	A Model for Characteristic X-Ray Emission in Electron Probe Microanalysis Based on the (Filtered) Spherical Harmonic () Method for Electron Transport. <i>Microscopy and Microanalysis</i> , 2022 , 28, 454-468	0.5	
22	Structure Analysis by Electron Diffraction Method. 2022 , 321-340		
21	Light emission properties of mechanical exfoliation induced extended defects in hexagonal boron nitride flakes. 2D Materials,	5.9	1
20	Spatial Resolution in Secondary-Electron Microscopy Microscopy (Oxford, England), 2022,	1.3	1
19	The effect of secondary electrons on radiolysis as observed by in liquid TEM: the role of window material and electrical bias. <i>Ultramicroscopy</i> , 2022 , 113579	3.1	
18	Ultrafast scanning electron microscopy with sub-micrometer optical pump resolution. <i>Applied Physics Reviews</i> , 2022 , 9, 021418	17.3	1
17	Structure Analysis Using Time-of-Flight Momentum Microscopy with Hard X-rays: Status and Prospects. <i>Journal of the Physical Society of Japan</i> , 2022 , 91,	1.5	0
16	Test Objects with a Rectangular Profile for SEM. 4. Amplitude Measurements on a SEM. 2022 , 16, 797-80	05	O
15	Test Objects with a Rectangular Profile for SEM. 5. Mechanisms of SEM Signal Formation. 2022 , 16, 806-	819	O
14	Quantitative analysis of backscattered-electron contrast in scanning electron microscopy.		O
13	Segmentation of SEM images of multiphase materials: When Gaussian mixture models are accurate?.		O
12	Uncovering the Emotional Aspect of Inquiry Practices in a Remote SEM Environment and the Development of a Designated Questionnaire.		O
11	Touchless Potential Sensing of Differentially Charged Spacecraft Using X-Rays. 1-11		0
10	Improvement of Quantitative STEM/EDXS Analyses for Chemical Analysis of Cu(In,Ga)Se2 Solar Cells with Zn(O,S) Buffer Layers.		O
9	Room Temperature Viscous Flow of Amorphous Silica Induced by Electron Beam Irradiation. 2205237		О
8	Effects of excess electrons/holes on fracture toughness of single-crystal Si. 2023 , 133, 035101		O

CITATION REPORT

7	Low-Aberration ExB Deflector Optics for Scanning Electron Microscopy.	Ο
6	Electron-Beam-Induced Carbon Contamination in STEM-in-SEM: Quantification and Mitigation.	1
5	Electric Potential Estimation of Inhomogeneous and Differentially Charged Objects Using X-Rays. 2023 ,	O
4	Optical probing of spatial structural abnormalities in cells/tissues due to cancer, drug-effect, and brain abnormalities using mesoscopic physics-based spectroscopic techniques.	O
3	Use of electron backscatter diffraction patterns to determine the crystal lattice. Part 1. Where is the Bragg angle?. 2023 , 56, 349-360	O
2	Use of electron backscatter diffraction patterns to determine the crystal lattice. Part 2. Offset corrections. 2023 , 56, 361-366	O
1	A Ray Tracing Model for Electron Optical Imaging in Electron Beam Powder Bed Fusion. 2023 , 7, 87	О